

Search Notes

Application/Control No.

10/647,433

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

MIMURA ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	711	4/12/2006	BT
438	719	4/12/2006	BT
438	728	4/12/2006	BT
438	729	4/12/2006	BT

INTERFERENCE SEARCHED

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438	711	4/12/2006	BT
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438/729		4/12/2006	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated keywords search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	4/12/2006	BT